Fabrication of Fully Inkjet-Printed Vias and SIW Structures on Thick Polymer Substrates

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Abstract—In this paper, a novel fully inkjet-printed via fabrication technology and various inkjet-printed substrate-integrated waveguide (SIW) structures on thick polymer substrates are presented. The electrical properties of polymethyl methacrylate (PMMA) are thoroughly studied up to 8 GHz utilizing the T-resonator method, and inkjet-printable silver nanoparticle ink on PMMA is characterized. A long via fabrication process up to 1 mm utilizing inkjet-printing technology is demonstrated, and its characteristics are presented for the first time. The inkjet-printed vias on 0.8-mm-thick substrate have a resistance of ~0.2 Ω. An equivalent circuit model of the inkjet-printed stepped vias is also discussed. An inkjet-printed microstrip-to-SIW interconnect and an SIW cavity resonator utilizing the proposed inkjet-printed via fabrication process are also presented. The design of the components and the fabrication steps are presented, and the measured performances over the microwave frequency range of the prototypes are presented.

Index Terms—Additive fabrication, inkjet-printed substrate-integrated waveguide (SIW), inkjet-printed via, low-cost via fabrication, polymethyl methacrylate (PMMA).

I. INTRODUCTION

INKJET-PRINTING technology is investigated and widely utilized as an alternative fabrication method to the conventional subtractive fabrication methods, such as milling and etching. The importance of green, scalable, and cost-efficient technology is ever increasing for numerous applications, such as the Internet of Things (IoT), the radio frequency identification (RFID) tags, and the wireless sensor networks [1]–[3]. The inkjet-printing technology does not produce any byproducts, because it only deposits the controlled amount of functionalized inks, such as silver nanoparticles on desired position. In addition, it is a completely dry process, which is compatible with most modern fabrication processes [4]. Arbitrary geometries with small feature sizes (<50 μm) can be printed on numerous substrates without any special masking [5]–[7]. Recently, the development of various types of nanoparticle-based inks, such as polymers, carbon nanotubes, piezoelectric materials, and high dielectric constant materials, has attracted significant interest from many researchers [8]–[11]. Numerous studies and applications utilizing inkjet-printing technology in microwave area have been reported, including inkjet-printed wireless power transfer topologies, RFID-based sensors, and microwave components for high-speed communication systems [12], [13]. However, most of these works are single-layered structures, because it is challenging to realize the inkjet-printed vias, which are one of the most critical factors for the realization of highly integrated systems, packages, and multilayered structures.

In this paper, the implementation of inkjet-printed stepped vias on thick substrates (thickness > 100 μm) is presented for the first time. Only a small number of technologies for implementing vias utilizing the inkjet-printing technology have been reported, all of which have been implemented on thin substrates with thickness below 100 μm [14]–[18]. Such thin substrates are unsuitable for applications in relatively lower frequency bands, such as mobile, WiFi, Industrial, Scientific, and Medical, and so on. The feature size of microwave components, such as the width of microstrip line, is narrow on thin substrate, which results in high design sensitivities to fabrication tolerances. On the other side, the radiation efficiency of antennas, such as patches, resonators, and waveguide structures [such as substrate-integrated waveguides (SIWs)], is significantly affected by the substrate thickness [19]. Therefore, it is necessary to develop via fabrication concepts or techniques, which can be applied to various substrates of different thicknesses. The major issue in the metallization of via holes utilizing the inkjet-printing technology is to maintain a continuous and uniform metal layer, since the printed traces shrink after the sintering process, which is challenging because the inkjet-printed silver nanoparticles shrink during the sintering process. Cylindrical copper pillars were inserted in laser-drilled via holes to metalize the thick via holes [20]. High conductivity and thick metal thickness compared with those of the printed nanoparticle-based metallic layers can be achieved by using this technology, since thick copper pillars are utilized. However, it has limited design degrees of freedom because the size of copper pillar
(i.e., length, radius, and so on) is fixed, and an additional soldering process is required to ensure the contact between the planar metallic layers and the copper vias.

In this paper, a novel via hole topology with an exponentially tapered profile is introduced in order to facilitate the formation of continuous metal layers using conductive inks. As a proof-of-concept demonstration of the proposed inkjet-printed stepped-via configuration, an equivalent circuit model and an SIW structure, such as a microstrip-to-SIW transition, are presented on the polymethyl methacrylate (PMMA) substrate. A via array and an SIW cavity resonator are also presented on RT/Duroid 5880 to verify the repeatability of the via fabrication process and its performance. SIW structures require a large number of vias, which make them good benchmarking structures to test the repeatability and the performance of the proposed stepped vias. PMMA, which is also known as Plexiglas or acrylic, is a widely used commercial polymer material for numerous applications, such as display devices and medical instruments, due to its high transparency and good compatibility with human tissues [21]. However, the electrical properties of PMMA at microwave frequency range as well as the characteristics of inkjet-printed silver nanoparticles on PMMA are not well known. Therefore, PMMA is chosen as a substrate, and its electrical properties are characterized for the first time in this paper. In addition, the demonstration of the first fully inkjet-printed SIW structures suggests the importance of inkjet-printing technology toward implementing the system-on-substrate concept in communication, sensing, and IoT applications [13], [19].

In Section II, the characterization of PMMA and inkjet-printed silver nanoparticles on PMMA is presented, while in Section III, the fabrication process of inkjet-printed stepped via is introduced. Section IV introduces the first fully inkjet-printed SIW structures, including an SIW cavity resonator and a microstrip-to-SIW transition.

II. INKJET-PRINTING PROCESS ON PMMA SUBSTRATE

PMMA was chosen as the substrate for the realization of the via-enabled structures in this paper, because its electrical properties at microwave frequency range were not clearly reported although it is widely utilized for microwave applications, such as in microfluidic sensors. A thorough characterization of the inkjet-printed silver nanoparticles on PMMA is necessary in order to extend the capabilities of inkjet-printed technologies to include via metallization and fabrication of SIW topologies.

In this section, the properties (conductivity and thickness) of inkjet-printed conductive traces using silver nanoparticles on PMMA substrate are investigated, while the electrical properties of PMMA are characterized within the microwave frequency range (1~8 GHz) utilizing the T-resonator method [22].

A. Inkjet-Printed Silver Nanoparticles on PMMA

The properties of inkjet-printed silver nanoparticles have different values depending on the substrate properties. It is because different substrates have different physical surface properties, such as roughness, surface energy, and contact angle with the ink, that result in different inkjet-printability and printing challenges [23].

Simple rectangular traces (0.5 mm × 5 mm) were printed on PMMA substrate (Goodfellow, London, U.K. [24]) in order to investigate the properties of inkjet-printed silver nanoparticles on PMMA. The DMP2800 inkjet printer was utilized to print silver nanoparticles in this paper. For printing, the Dimatix 10-pL cartridge (DMC-11610) was used, and it was kept at a distance of 250 μm from the surface of the substrate. The printer head angle was 4.5°, which achieves a printing resolution of 1270 dpi. Cabot conductive ink CCI-300 was jetted at a nozzle temperature of 36 °C, while the substrate was maintained at room temperature (25 °C). Fig. 1(a) shows the thickness of the printed silver nanoparticle-based lines depending on the number of printed layers. The printed patterns were sintered at 120 °C for 2 h, and the thickness was measured using a Veeco Dektak 150 surface profilometer. Each printed layer added about 500 nm of thickness to the printed traces. A reported minimum feature size of the silver nanoparticle ink using a commercially available printer is ~50 μm up to five layers of printing. After printing the third layer, the coffee ring effect has been observed because of the high surface energy of PMMA. The high surface energy of PMMA results in different drying speeds of ink at the edge and middle of the printed patterns [25], [26]. The width of the printed trace is additionally increased by ~80 μm for each additional printed layer when the thickness (height) of the printed traces has exceeded 1.5 μm. The inkjet-printing technology is a thin metal process that the thickness of printed traces, such as metals and polymers, is about one skin depth or less at the microwave frequency range. However, it takes the advantage of flexibility, ease of fabrication, and cost efficiency of the printing technology, which are the critical properties for implementing novel applications, such as IoT. The conductivity (σ) of the inkjet-printed silver nanoparticles was also extracted using the measured profiles of the printed traces using

$$\sigma = \frac{l}{R \cdot A} \text{ (S/m)}$$

where $l$ is the length of the trace, $R$ is the resistance across the trace, and $A$ is the cross section area of the trace. The cross section areas of the printed traces were numerically integrated over the line width [Fig. 1(a)]. Fig. 1(b) shows the extracted conductivities for different sintering temperatures as a function of the number of printed layers. The conductivity value converges after printing three layers, because the particle density is saturated. Higher sintering temperatures resulted in higher conductivity values, as reported in [13] and [27]. The converged conductivity values of the silver nanoparticle ink were around $4.4 \times 10^6$ S/m at 120 °C, $5.7 \times 10^6$ S/m at 150 °C, and $6.9 \times 10^6$ S/m at 180 °C. It corresponds to 6.98%, 9.05%, and 10.95% of bulk silver’s conductivity ($\sigma_{Ag} = 6.3 \times 10^7$ S/m), respectively.

B. RF Characterization of PMMA

A commercially available PMMA sample has been characterized up to 8 GHz through the microstrip T-resonator...
Fig. 1. Thickness and conductivity of inkjet-printed traces. (a) Thickness. (b) Conductivity.

Fig. 2. Fabricated T-resonators and thru-reflection-line (TRL) calibration structures on 1-mm-thick PMMA. The T-resonators consist of 50-Ω feeding lines and an open stub. The length of the open stub is quarter-wavelength (λg/4) at the desired resonant frequency. The width of the microstrip feeding lines was 2.8 mm, and the length of the T-resonator for 1 GHz is 51.92 mm and for 2 GHz is 25.56 mm. Fig. 3 shows the measured S21 of the fabricated T-resonator for 1 GHz. The measurement and simulation results are in good agreement. The resonant frequencies (fn) of the T-resonator can be determined by

\[ f_n = \frac{n \cdot c}{4(L_{\text{phy}} + L_O - L_T) \sqrt{\varepsilon_{\text{eff}}}} \]  

where \( n \) is the odd resonance mode order (\( n = 1, 3, 5 \ldots \)), \( c \) is the speed of light in free space, \( L_{\text{phy}} \) is the physical length of the open stub, \( L_O \) is the correction factor for the open-end effect of the open stub, \( L_T \) is the correction factor for the T-junction effect, and \( \varepsilon_{\text{eff}} \) is the relative effective permittivity [22].

The loss tangent (tan \( \delta \)) of the PMMA substrate was extracted from the quality factor (\( Q \)) of each resonance, as reported in [22]. The conductor losses were theoretically estimated using the equations reported in [30], and the radiation losses were also theoretically calculated utilizing 3-D full wave simulator, ANSYS High Frequency Structural Simulator (HFSS) v11.1.1. A thin copper sheet (thickness = 100 μm and \( \sigma = 5.8 \times 10^7 \text{ S/m} \)) was utilized as the metal layer.

The coaxial SubMiniature version A (SMA) connectors were mounted using a conductive silver epoxy, and TRL calibration was applied to deembed the effects of feeding lines and the SMA connectors. The extracted effective permittivity (\( \varepsilon_{\text{eff}} \)) was converted into relative permittivity (\( \varepsilon_r \)). The resulting relative permittivity (\( \varepsilon_r \)) was 2.38 ± 0.12, and the extracted tan \( \delta \) was 0.011 ± 0.002 over the frequency of 1~8 GHz band, as shown in Fig. 4. The error intervals were estimated for a 99% confidence interval. Characterization results using the two-line-method are included in Fig. 4 for validation purpose [32]. Two transmission lines with the same characteristic impedance and two different lengths (20 and 70 mm) were prepared on the same substrate, and their scattering parameters (S21) were measured. The lengths of the transmission lines were corresponding to effective

Fig. 3. \( S_{21} \) of the 1-GHz T-resonator.
electrical length of 30° and 100° at 1 GHz, respectively. These transmission lines were utilized as the delay lines for TRL calibration. The relative dielectric constants ($\varepsilon_r$) over the frequency range of operation were extracted from the phase difference of the test transmission lines, and the values of tan $\delta$ over the frequency were calculated from the attenuation constant ($\alpha$) of the transmission lines. The calculated radiation loss using 3-D electromagnetic simulator of the transmission line was subtracted from the measurement. These results are in good agreement and support the extracted values from the T-resonator method. The extracted dielectric constant values from the T-resonators vary compared with the values from the transmission line method. It is because of the fabrication error of each resonator, since the T-resonators were cut out from a copper tape. However, the extracted values from each resonators, such as a T-resonator for 1 GHz (resonant frequencies: 1, 3, 5, and 7 GHz), are robust over the frequency band.

III. INKJET-PRINTED VIA

In this section, a novel via fabrication process on thick substrates utilizing the inkjet-printing technology is presented. In previously reported research efforts, inkjet-printed via holes have been successfully implemented on thin substrates [14]–[18], as shown in Table I. In [14], the three layers of silver nanoparticles have been printed over a thin vertical wall utilizing 50-pL cartridge. In [15], a craterlike via hole is made by inkjet printing an ethanol drop to dissolve a polyvinyl phenol layer. In [16], a microvia array, which consists of small laser-drilled microvias, is presented on polyimide substrate. In [17] and [18], the printed microwave structures, such as microstrip lines, are presented, and the reported loss of printed microstrip lines is about 0.3~0.5 dB/mm up to 10 GHz. The reported printed vias shown in [14]–[18] are built on a thin substrate, whose thickness is <100 $\mu$m. The proposed stepped-via approach (with a 2-mm diameter) achieved the via thickness of 800~1000 $\mu$m with a good via resistance of 0.2 $\Omega$ compared with the reported works.

It is challenging to metalize via holes on relatively thick substrates. If the via holes are metalized with a similar approach to other inkjet-printed structures, i.e., printing multiple layers on drilled via holes, it results in discontinuities, as shown in Fig. 5. For demonstration purposes, a straight via hole was drilled on 1-mm-thick PMMA using CO$_2$ laser, and
silver nanoparticles were printed over the via hole five times. The printed via hole was sintered at 120 °C for 1 h. The printed silver nanoparticles failed to form a continuous metal layer on the via hole because of the shrinkage of the silver ink during the sintering process due to the evaporation of the solvents, the polymers (a dispersant on the silver nanoparticles), and the impurities of the ink. The gravity force further enhances the downward shrinkage of the ink, which results in cracks on the metalized via wall. The shrinkage of the inkjet-printed silver nanoparticles on the vertical via wall is briefly shown in Fig. 5(a). The inkjet-printed silver nanoparticles on the vertical wall are shrinking in different directions, and these results in cracks, as shown in Fig. 5(b).

A novel stepped-via hole topology is introduced in order to create a gradual transition between the top and bottom planar substrate surfaces and reduce the stress on printed silver nanoparticles on the via hole during the sintering process. The fabrication process is described in Fig. 6. A thin concentric circular cylinder is engraved on the substrate to form a stepped-via profile [Fig. 6(a-i) and (a-ii)]. Then, the substrate is flipped to drill another stepped via on the bottom side [Fig. 6(a-iii) and (a-iv)]. It is necessary to form a smooth transition from the via top to the bottom of the substrate. The final step is the inkjet-printing process [Fig. 6(a-v) and (a-vi)]. The fabricated stepped-via hole on PMMA is shown in Fig. 6(b).

This fabrication process is suitable for the inkjet printing, because the drilling process and the inkjet-printing process are completely separate, while the via metallization is easily achieved during the inkjet printing (totally dry) process without any additional steps. The fabrication concept shown here on the PMMA substrate is for the proof-of-concept only, and is equally applicable to any other inkjet-printable substrates.

The fabricated inkjet-printed vias are shown in Fig. 7 and Fig. 8. The geometries of the stepped via (top and side views) are shown in Figs. 7(a) and 8(a). Five concentric disks were drilled to form a stepped-via profile on the top, and two concentric disks were drilled on the bottom. A symmetric via profile (the same number of disks on the top and the bottom) requires the precise control of the laser power level and alignment to match each end of the drilled stepped-via topology, which is more significantly challenging than the asymmetric stepped-via topology. The ratio of the drilled disks is kept to the same value. The two concentric disks on the bottom with gradually increasing radii make sure that the penetration of the via hole runs through the entire substrate, because the upper five concentric disks with gradually decreasing radii sometime fail to form a through hole due to the misalignment of the laser focus or uneven substrate surface. The bottom disks also improve the metal continuity, because they enable a smoother transition from the via to the bottom by chamfering the transition from the via to the bottom layer. The disk radii of \( R_1 \) and \( R_2 \) are chosen for the bottom disks to facilitate the alignment and the fabrication, since misalignment and fabrication errors can be compensated within the larger radii \( R_1 \) and \( R_2 \). The equal via radii at the top and bottom via disks assist in the easier continuation of the layout at the top layer to the layout at the bottom layer. The radius of each circular disk is shown in Fig. 7(a), featuring exponentially tapered values \( r_{n+1} = e^{-1} \cdot r_n \).

A universal laser system’s PLS6.75 CO\(_2\) laser was utilized. The laser was raster-scanned over the concentric circles at 1.4 W in a speed of 71 cm/s and a resolution of 1000 pulses per inch (PPI). Five layers of silver nanoparticle ink were printed over the engraved stepped-via hole using the same inkjet-printing machine and settings discussed in Section II-A. The printed via sample was sintered at 120 °C for 2 h. Scanning electron microscope (SEM) images are shown in Figs. 7(b) and 8(b). Quanta 3-D FEG SEM tool was utilized in this paper. Fig. 7(b)-A shows the semicircular area of the inkjet-printed stepped via, which corresponds to a dashed box in Fig. 7(a) (top view). The stepped profile of via is clearly observed with continuous metallization [Fig. 7(b)-A].
Fig. 7. (a) Geometry of stepped-via hole. (b) SEM images of the metalized stepped-via hole (top view).

Fig. 8. (a) Geometry of stepped-via hole. (b) SEM images of the metalized stepped-via hole (side view).

Fig. 7(b)-A1–A3 shows the magnified SEM images of corresponding areas shown in Fig. 7(b)-A. Fig. 7(b)-A1 shows a planar area of the inkjet-printed stepped via. Fig. 7(b)-A2 shows the transition from the surface of the top substrate to the stepped via and Fig. 7(b)-A3 shows the transition between two consecutive stepped-via disks. The rough surface of the via hole is due to the laser raster scanning, which utilizes a pulse laser. The profile of the stepped-via hole is also shown in Fig. 8 (side view). Fig. 8(b)-B shows the area of the dashed boxes in Fig. 8(a). The depth of each step was \( \sim 140 \, \mu m \), and a continuous silver nanoparticle layer was observed throughout the entire stepped-via hole. Fig. 8(b)-B1–B3 shows the magnified SEM images of corresponding areas shown in Fig. 8(b)-B and B1. The silver nanoparticles form a solid layer along the via hole [Fig. 8(b)-B2 and B3], and a smooth transition from top to bottom is observed [Fig. 8(b)-B3]. The transition boundary between the silver nanoparticle layer and the PMMA substrate is shown in dashed line in Fig. 8(b)-B3. The proposed via fabrication process is compatible with the inkjet-printing technology as well as a cost-efficient process, since this process etches small volume of substrate material. A volume of seven-stepped-via hole shown in Figs. 7 and 8 is 1.03 mm\(^3\), while a volume of a conventional cylindrical-via hole that has the same via radius of 1 mm is 3.14 mm\(^3\). The equivalent radius of the conventional cylindrical-via hole that has the same etched volume is 0.57 mm.

A via chain that consisted of 5–40 inkjet-printed stepped vias was fabricated on 0.8-mm-thick Rogers RT/Duroid 5880, and the vias’ dc resistance was measured to verify the repeatability and the robustness of the proposed fabrication process. The RT/Duroid 5880 was chosen to demonstrate the easy scalability of the proposed via topology, as it features low-loss tangent at gigahertz frequency range as well as high-temperature handling capability. The via chain was connected in a series. The measured resistances of the via arrays were 3.7 \( \Omega \) for the 20 vias and 7.2 \( \Omega \) for the 40 vias. The average resistance of the each inkjet-printed stepped via was \( \sim 0.2 \, \Omega \), as shown in Fig. 9. The via resistances on PMMA and Rogers RT/Duroid 5880 are different because of substrate thickness and surface energy of the substrates. The thickness of RT/Duroid 5880 is 20% thinner than one of the PMMA. The RT/Duroid 5880 has higher surface energy than the PMMA resulting in thicker metal trace when silver nanoparticle ink is printed.

**IV. VIA MODELING**

A typical cylindrical via can be modeled as an inductor and a resistor in series. Circuit models for a straight cylindrical via and for a generalized stepped via are shown in Fig. 10.
The proposed stepped via can be considered as a series of cylindrical vias [Fig. 10(a)], as shown in Fig. 10(b). The transition between the adjacent cylinders, such as $D_2$, $D_1$, and $D_{n-k+1}$, can be easily achieved when both the top and bottom sides are printed one by one, as discussed in Section III. The equivalent shunt capacitance of the stepped via is negligible when the length of the stepped via is much smaller than a wavelength at the operation frequency. For simplicity and without the loss of generality, the cylinder on the bottom is chosen to have the same dimensions with the cylinders on the top, as shown in Fig. 10(b), and their equivalent circuit model (an inductance value and a resistance value) is derived based on the geometry of the vias. An inductance value ($L_{eq}$) and a resistance value ($R_{eq}$) of a straight cylindrical via can be expressed, as shown in (3) and (4), where the radius of the cylindrical-via hole is $r_{eq}$, the metal thickness is $t$, and the height of the via is $H$

$$
\begin{align*}
L_{eq} &= \frac{\mu_0 H}{4\pi} f(r_{eq}, t) \\
R_{eq} &= \frac{\sigma \pi}{2} g(r_{eq}, t)
\end{align*}
\tag{3}
$$

where

$$
\begin{align*}
f(r_{eq}, t) &= \frac{r_{eq}^2 - (r_{eq} - t)^2 - 2(r_{eq} - t)^2 \ln\left(\frac{r_{eq}}{r_{eq} - t}\right)}{r_{eq}^2 - (r_{eq} - t)^2} \\
g(r_{eq}, t) &= \frac{1}{t(2r_{eq} - t)}
\end{align*}
\tag{4}
$$

Similarly, the circuit model ($L_s$ and $R_s$) of the proposed stepped-via hole can be derived based on (3) and (4), as shown in

$$
\begin{align*}
L_s &= \frac{\mu_0 h}{4\pi} \left[ 2 \sum_{i=1}^{n} f(r_i, t) + \sum_{i=n-k+1}^{n} f(r_i, t) \right] \\
R_s &= \frac{\sigma \pi}{2} \left[ h \left( \sum_{i=1}^{n} g(r_i, t) + \sum_{i=n-k+1}^{n} g(r_i, t) \right) \\
&+ \sum_{i=1}^{n-1} h(r_{i+1}, r_i, t) + \sum_{i=n-k+1}^{n} h(r_{i+1}, r_i, t) \right] \\
\text{(}N = n + k, \ k \geq 1\text{)}
\end{align*}
\tag{5}
$$

$$
\begin{align*}
f(r_i, t) &= \frac{r_i^2 - (r_i - t)^2 - 2(r_i - t)^2 \ln\left(\frac{r_i}{r_i - t}\right)}{r_i^2 - (r_i - t)^2} \\
g(r_i, t) &= \frac{1}{t(2r_i - t)} \\
h(r_{i+1}, r_i, t) &= \frac{t}{(r_{i+1} - t)^2 - (r_i - t)^2}
\end{align*}
\tag{6}
$$

The performance of the inkjet-printed via, such as the cutoff frequency, the inductance, and the resistance of the printed via, is a strong function of the via radius based on (5) and (6). A via segment with the smallest radius is the most important segment of the proposed stepped-via topology, since the inductance increases exponentially as the radius decreases, while the resistance is inversely proportional to the via radius.

The proposed stepped-via topology is easy to fabricate utilizing the inkjet-printing technology, but it is impractical to model every different stepped-via topologies in full-wave 3-D simulators, such as HFSS and Computer Simulation Technology. It is convenient to derive an effectively equivalent straight cylindrical via circuit model, where the composite inductance and resistance values are the same with the proposed stepped via. The five-layered stepped via was assumed on 0.8-mm-thick RT/Duroid 5880, as shown in Fig. 10, as a design example. The height of each cylinder ($h$) was 200 $\mu$m, the radius of the largest cylinder ($r_4$) was 1 mm, and the metal thickness ($t$) was set to 210 nm with a conductivity value of $9 \times 10^6$ S/m.

Fig. 9. Measured dc resistance of the via chain. Inset: inkjet-printed stepped-via array.

Fig. 10. (a) Equivalent circuit model of a stepped via. (b) Equivalent via model of a cylindrical via and a stepped via.
The radii were exponentially increased \((r_{n+1} = e \cdot r_n)\). The equivalent circuit model \((L_{eq} \text{ and } R_{eq})\) of a cylindrical via was designed based on (3)–(6). The equivalent radius \((r_{eq})\) of a cylindrical via was 360 \(\mu\)m with a metal thickness of 180 nm and a conductivity value of \(1 \times 10^7\) S/m. Each value was calculated from the proposed equations (3)–(6). The designed equivalent circuit model of the cylindrical via has the same inductance and resistance with those values of the stepped via \((L_{eq} = L_s = 45.28 \, \text{pH} \text{ and } R_{eq} = R_s = 0.2 \, \Omega)\). The resistance value agrees with the measurement shown in Fig. 9. The simulated equivalent via and stepped-via models at microwave frequency band are shown in Fig. 11, and the results agree very well.

V. INKJET-PRINTED SIW COMPONENTS

An SIW technology is one of the most promising technologies for high-frequency applications, and numerous studies have been reported at the microwave frequency band [19]. However, there are not many reported works on printed SIW components, including via metallization methods, using a printing technology. The results of the inkjet-printed stepped vias and the substrate characterization at microwave frequency range suggest that the relatively high conductivity values of inkjet-printed silver nanoparticles \((4.6 \times 10^6 \sim 8 \times 10^6 \, \text{S/m})\) and fabrication of numerous vias can be easily achieved. As a proof of the via fabrication concept and its application, various SIW components with large number of vias were designed, and the prototypes were experimentally investigated. Therefore, in this paper, SIW structures are chosen as a design example utilizing the proposed stepped-via topology to implement fully printed SIW components. In this section, a microstrip-to-SIW transition and an SIW cavity resonator are presented.

A. SIW Cavity Resonator

An inkjet-printed SIW cavity resonator has been designed to verify the performance of the inkjet-printed vias. The cavity was designed to resonate at 5.8 GHz on 0.8-mm-thick Rogers RT/Duroid 5880 \((\varepsilon_r = 2.2 \text{ and tan } \delta = 0.0009 \text{ at } 10 \, \text{GHz})\) in order to minimize the effect of substrate loss. The geometry of the designed SIW cavity is shown in Fig. 12. The top and bottom sides of the substrate were drilled utilizing a laser to form a stepped-via profile, as discussed in Section III. The designed pattern was printed five layers on the top side, and a 45 mm \(\times\) 40 mm patch was printed on the bottom side as a ground plane.

The measured and simulated reflection coefficients \((S_{11})\) are shown in Fig. 13. The results match reasonably well, and their small discrepancy is due to fabrication errors stemming from the dispersion of ink on substrate after printing. The quality factor \((Q\)-factor\) of the fabricated SIW cavity is calculated using

\[
Q = \frac{f_r}{\Delta f_{3dB}}
\]

where \(f_r\) is the resonant frequency and \(\Delta f_{3dB}\) is the 3-dB bandwidth (half power bandwidth). The measured resonant frequency was 5.79 GHz, and the 3-dB bandwidth was 0.23 GHz, which results in a \(Q\)-factor of 25.13, while the simulated \(Q\)-factor was 20.05 at 5.73 GHz. The achieved \(Q\)-factor of the inkjet-printed SIW cavity was relatively low compared with the conventional cavity resonators [33], [34], since the inkjet-printed metallic layer has thin metal thickness (\(<5 \, \mu\)m) and a relatively low conductivity value compared with a bulk copper \((\sigma_{\text{printed}} = 9 \times 10^6 \, \text{S/m} \text{ and } \sigma_{\text{cu}} = 5.96 \times 10^7 \, \text{S/m})\) resulting in a high loss from metal layers.
B. Inkjet-Printed Microstrip-to-SIW Transition

A simple microstrip-to-SIW transition on PMMA has been designed, and it was fully inkjet-printed by utilizing the stepped-via structure for the first time. Its fundamental mode cutoff frequency \( f_0 \) has been set to 4 GHz in order to enable an operating frequency of 5 GHz. The geometry of the proposed microstrip-to-SIW transition is shown in Fig. 14(a). Each corner of PMMA was bent due to the thermal expansion of the substrate, but the middle of the SIW was flat. The SIW and the tapered transition were designed and optimized by following the reported design guide described in [35] and [36]. The width \( W_{\text{SIW}} \) and the length \( L_{\text{SIW}} \) of the SIW were 24 and 23 mm, respectively. The diameter \( D_{\text{via}} \) and the pitch \( P_{\text{via}} \) of the stepped vias were both equal to 2 mm. The length \( L_{\text{taper}} \) of the tapered microstrip-to-SIW transition was 12 mm, and the width \( W_{\text{taper}} \) of it was 6 mm. The thickness of the substrate is 1 mm. Fig. 14(b) shows the fully inkjet-printed microstrip-to-SIW transition on PMMA. Vias were drilled as introduced in Section III, and then, the SIW pattern and the ground plane were printed. The printer settings and the sintering temperature were the same, as presented in Section II-A.

The measured and simulated values of the magnitude of the scattering parameters \( |S_{11}| \) and \( |S_{21}| \) are shown in Fig. 15, demonstrating good agreement. The measured insertion loss of the proposed microstrip-to-SIW at 5 GHz is 2.4 dB. It is notable that the inkjet-printed vias have been successfully implemented.

VI. CONCLUSION AND FUTURE WORK

In this paper, the inkjet-printing process of silver nanoparticles on thick substrates, such as a PMMA and RT/Duroid 5880, for microwave applications as well as the fabrication process of fully inkjet-printed low-cost vias and SIW components is demonstrated. The inkjet-printed silver nanoparticle inks on PMMA feature good conductivity values \((4.5 \times 10^6 \sim 8 \times 10^6 \text{ S/m})\) to implement practical microwave topologies. The fully inkjet-printed vias on the PMMA substrate were implemented by introducing a novel stepped-via hole configuration with an exponentially tapered radial profile. As a proof-of-concept, fully inkjet-printed SIW structures, such as an SIW cavity resonator and a microstrip-to-SIW transition, were designed and experimentally demonstrated, verifying the feasibility of inkjet-printed stepped vias on various substrates.

The work presented in this paper is a fundamental study toward the future fully inkjet-printed low-cost via-enabled devices and systems, including packaging. The next step of this paper is to increase the thickness of the inkjet-printed silver nanoparticle films in order to reduce the skin depth effect. A proper surface treatment, such as the modification of the surface energy (surface functionalization or ozone treatment), and applying mechanical constraints (increase surface roughness or implement channel for the inks) [37], could improve the printable thickness, adhesion, and uniformity of silver nanoparticles.

REFERENCES


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